

Burn-In for Gate Drivers



Enhanced Field Reliability

Applications

- Mission-critical and high reliability systems
- Transportation
- Electrical generation and transmission

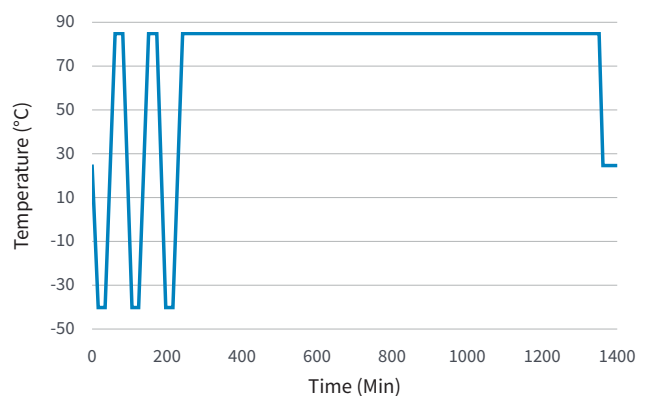
Burn-In Process

- 100% production test
- Burn-in profile
 - 23 hour burn-in cycle
 - Controlled oven profile
 - Three cycles -40 °C to +85 °C (258 minutes)
 - 1092 minute dwell-time at 85 °C
 - 30 minute off-time at 25 °C
 - Customer-specific burn-in profile on request

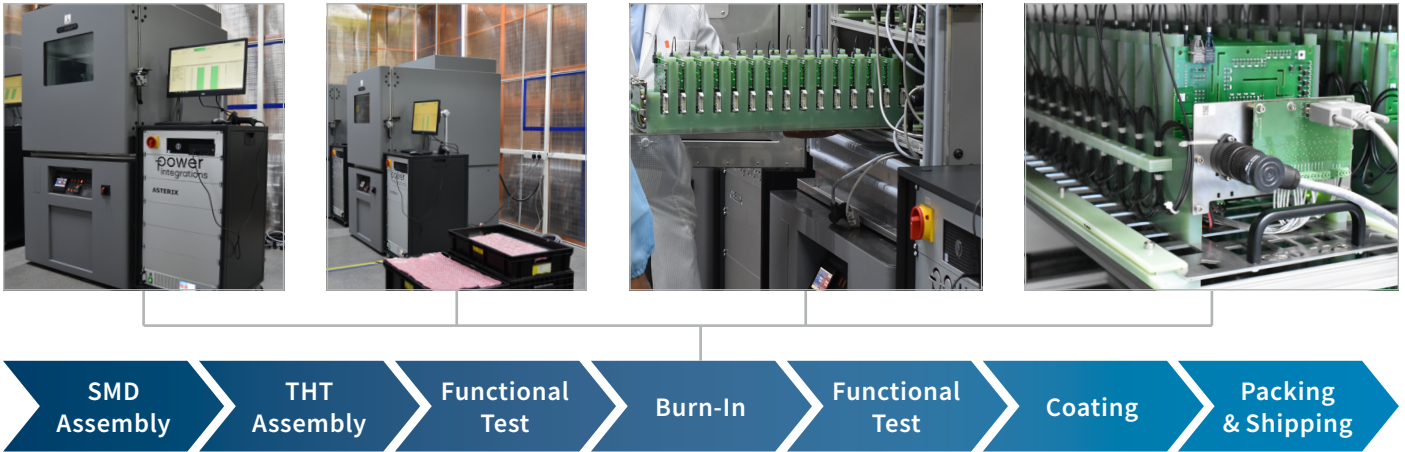
Key Features

- Reduces total cost of ownership and streamlines production
- Eliminates challenges posed by in-house solutions and removes the need for specialized subcontractors
- Reduces failure rate by up to 15 PPM
- Extended warranty available with burn-in

Burn-In Profile



Burn-In – In-Line Process Flow



Increase Reliability

Power Integrations gate driver products for demanding applications with >100,000 hour operating lifetime. Burn-in test eliminates infant mortality improving system reliability and reducing maintenance challenges.

